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 Applicant  
Etsuo KAWATE

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**U.S. PATENT DOCUMENTS**

*Examiner Initial	Document Number	Date	Name	Class	Sub Class	Filing Date

**FOREIGN PATENT DOCUMENTS**

	Document Number	Date	Country	Class	Sub Class	Translation	
						YES	NO
/M.L./	01/65239	Sept. 7, 2001	WIPO			N/A	

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

/M.L./	Stephen E. Ralph et al., "Terahertz Spectroscopy of Optically Thick Multilayered Semiconductor Structures," <i>Journal of the Optical Society of America</i> , Vol. 11, No. 12, December 12, 1994, pp.2528-2532.
/M.L./	Etsuo Kawate et al., "Expanding Optical Measurement Methods of Thin Films in the Far-infrared Towards the Lower Frequency Region," <i>THz 2003 Technical Digest</i> , 11th International Conference on Terahertz Electronics, p. 129, September, 2003.

Examiner /Michael Lapage/

Date Considered 09/16/2008

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.